

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10580052	AKASHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Dawn L Garrett	1794

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
428	690, 917 (see EAST history for all listed class/subclasses)	9-23-2008	DG
313	504, 506	9-23-2008	DG
257	40, E51.051	9-23-2008	DG
564	434	9-23-2008	DG

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
STIC structure search by EIC 1700 (M. Huang) (see attached printouts)	9-23-2008 and 9-24-2008	DG
STN search of registry numbers (see attached)	9-23-2008	DG
EAST search (see printout); Databases: EPO, JPO, DERWENT, USPAT, USPGPUB	9-23-2008 and 9-24-2008	DG
Inventor Name Search	9-23-2008	DG

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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